

**Search Notes**

Application/Control No.

10/705,892

Examiner

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Applicant(s)/Patent under  
Reexamination

LEE, SU-JEONG

Art Unit

2165

**SEARCHED**

Class	Subclass	Date	Examiner
707	2, 203	5/22/2006	J.V
707	103R	5/22/2006	J.V
707	103X	5/22/2006	J.V
707	103Y	5/22/2006	J.V
707	103Z,206	5/22/2006	J.V
717	1-4	5/22/2006	J.V
709	202,206	5/22/2006	J.V
709	251,302	5/22/2006	J.V

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EIC Plus database search	4/17/2006	J.V
consulted with F. coby primary AU 2161	5/19/2006	J.V
Inventor(s) search for possible double patenting	5/19/2006	J.V
East electronic database search	5/22/2006	J.V